

**EXHIBIT "A"**

**VERSION WITH MARKINGS TO SHOW CHANGES MADE**

**IN THE CLAIMS**

3. Raster probe microscope according to claim 1[ or 2],  
characterized by periodic raster-probe and/or sample oscillations.
5. Raster probe microscope according to claim 3[ or 4],  
characterized in that,  
the vertical oscillation of the raster probe (1) and/or of the sample (25) occurs with a first frequency of at least 10 Hz and a first amplitude of at least 1 nm.
7. Raster probe microscope according to claim 5[ or 6],  
characterized in that,  
the vertical oscillation of the raster probe (1) and/or of the sample (25) is additionally excited or modulated with a second frequency of at least 1 kHz and a second amplitude of at least 0.1 nm.
9. Raster probe microscope according to [one of claims 3 to 8]claim 3,  
characterized in that,  
the second raster-probe and/or sample oscillation is a horizontal oscillation with a frequency of at least 500 Hz and an amplitude of at least 0.1 nm.
11. Raster probe microscope according to [one of the preceding claims]claim 3,  
characterized by  
an evaluating arrangement (17) for the two measuring signals for the simultaneous determination of at least two material properties, comprising the adhesion, the static and dynamic friction, the surface topography as well as the elasticity and rigidity.
13. Raster probe microscope according to [one of the preceding claims]claim 3,  
characterized in that,  
the raster probe (1) is a point or tip (5) of a force microscope and/or of an optical near-field microscope.
17. Process according to [one of claims 14 to 16]claim 14,  
characterized in that,  
the vertical oscillation or the vertical oscillations has/have a frequency of at least 10 Hz and an amplitude of at least 1 nm.

19. Process according to claim 17[ or 18],  
characterized in that,  
on the vertical oscillation (or oscillations) there is superimposed at least one second  
oscillation with a frequency of at least 1 kHz and an amplitude of at 0.1 nm.
21. Process according to [one of claims 14 to 20]claim 14,  
characterized in that,  
the horizontal oscillation has a frequency of at least 500 Hz and an amplitude of at least  
0.1 nm.
23. Process according to [one of claims 14 to 22]claim 14,  
characterized in that,  
the raster probe (1) is brought into contact with the sample surface (30) with a determined  
normal or perpendicular force.
24. Process according to [one of claims 14 to 24]claim 14,  
characterized in that,  
for the evaluation of the measuring signals there is used a lock-in amplifier (17, 110)  
and/or a microcomputer (112).
25. Process according to [one of claims 14 to 24]claim 14,  
characterized in that,  
as raster probe (1) there is used the point or tip (5) of a force microscope and/or of an  
optical near-field microscope.
27. Process according to [one of claims 14 to 26]claim 14,  
characterized in that,  
the raster probe (1) and/or the sample (15) are subjected simultaneously at least to a  
vertical and at least to a horizontal oscillation.